Notice of Allowability	Application No.	Applicant(s)
	10/697,015	SHIZUNO, YOSHINORI
	Examiner	Art Unit
	Nitin Parekh	2811
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this or other appropriate communical GHTS. This application is subject	application. If not included tion will be mailed in due course. THIS
1. This communication is responsive to <u>06-24-05</u> .		
2. X The allowed claim(s) is/are 1-4, 6, 7, 18-20 and 22-24.		
3. The drawings filed on <u>06 June 2005</u> are accepted by the E	xaminer.	
4.	e been received. be been received in Application No cuments have been received in the of this communication to file a reflect of this application. iitted. Note the attached EXAMIN as reason(s) why the oath or declet be submitted. son's Patent Drawing Review (Pins Amendment / Comment or in the last of BIOLOGICAL MATERIA	nis national stage application from the ply complying with the requirements ER'S AMENDMENT or NOTICE OF aration is deficient. TO-948) attached the Office action of awings in the front (not the back) of 21(d). LL must be submitted. Note the
Attachment(s) 1. ☒ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☒ Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date ► 11-03-04 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Summ Paper No./Mail 08), 7. ☒ Examiner's Ame	Date
		Primary Examiner Technology Center 2800

Application/Control Number: 10/697,015 Page 2

Art Unit: 2811

DETAILED ACTION

Allowable Subject Matter

1. Claims 1-4, 6, 7, 18-20 and 22-24 are allowed.

Examiner's Amendment

- 2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- A. Cancel claims 9 and 21.
- B. Claim 19, line 15: Delete "and"
- C. At the end of claim 19, line 17: Insert "and a plurality of electrode posts formed between said wiring patterns and said external terminals, wherein said sealing portion is formed such that a top surface of said electrode posts is exposed." —-.

Authorization for this examiner's amendment was given in a telephone interview with Nick Bromer on 08-18-05.

Reasons for Allowance

2. The following is an examiner's statement of reasons for allowance:

The references of record do not teach either singularly or in combination at least the limitations "a base frame including a first surface, and a second surface which opposes said first surface, and including an opening portion formed through the base frame", "said semiconductor chip being disposed within said opening portion such that the level of said first main surface is substantially equal to the level of said first surface", "portions of said wiring patterns on a boundary and vicinity thereof between a region on the upper side of said semiconductor chip and the base frame being wider or thicker than other portions of said wiring patterns" and "a plurality of external terminals provided included over said wiring patterns in a region including the upper side of said base frame" in a resin sealed device having a semiconductor chip being disposed in the opening in a base frame, or "a silicon wafer constituting a base frame including a first surface, and a second surface which opposes said first surface, and including an opening portion formed through the base frame", "said semiconductor chip being disposed within said opening portion such that the level of said first main surface is substantially equal to the level of said first surface", and "a plurality of electrode posts formed between said wiring patterns and said external terminals, wherein said sealing portion is formed such that a top surface of said electrode posts is exposed" in a resin sealed device having a semiconductor chip being disposed in the opening in a silicon wafer and a plurality of wiring patterns being electrically connected to the respective electrode pads and external terminals.

Page 4

Art Unit: 2811

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nitin Parekh whose telephone number is 571-272-1663. The examiner can normally be reached on 09:00AM-05:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's acting supervisor, Steven Loke can be reached on 571-272-1657. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAN or Public PAG. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAG system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). Any inquiry of a general nature or relating to the

Art Unit: 2811

status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

NP

NITIN PAREKH

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08-18-05

PRIMARY EXAMINER

TECHNOLOGY CENTER 2800